

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BZX384-B62-Q						
		Nexperia DHAM Zener						
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
			TEST					
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, VR = 80 % of rated reverse						
# B1	Bias	voltage	1000 hours	250	11400	0		
		MIL-STD-750-1						
		M1038 Method B						
	SSOP	Tj = Tjmax, Iz = 100% of max. datasheet						
# B1b	Steady State Operational	reverse current	1000 hours	44	1920	0		
		150000 4404						
	TC	JESD22-A104	1000	244	1 1000	•		
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0		
	HUACT	JECD22 A110						
# 13 or	UHAST Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %						
# A3 or	Olibiased HAST	· · · · · · · · · · · · · · · · · · ·	- 96 hours	311	14080	0		
	46	JESD22-A102						
# A2 - It	AC Autoclave	Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)						
# A3 alt	Autociave	Plessure = 203 kPa (29.7 psia)						
	изтре	JESD22-A101						
	H3TRB	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# A2 alt	High Humidity High Temperature Reverse Bias	rated reverse voltage ^[1]	1000 hours	311	14080	0		
# AZ dit	remperature Reverse Blas	<u> </u>	1000 Hours	211	14000	U		
	IOL	MIL-STD-750 Method 1037						
# A5	Intermittent Operating Life	ton = toff, devices powered to insure $\Delta T_j = 100 \text{eV}$ for 15000 cycles	1000 hours	212	14120	0		
+ A3	Intermittent Operating Life	100 C for 13000 cycles	1000 hours	312	14120	0		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	269	8070	0		
+ CO	SD	200 0 = 3 0	10.2	209	0070	U		
# C10	Solderability	J-STD-002		19	6660	0		
+ CIU	Joine ability	J J1D 002	4451	13	0000	U		

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11400	0	0,37	2,68E+09

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